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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 1 of 1

Complete if Known	
Application Number	10/634,220
Filing Date	August 5, 2003
First Named Inventor	Kryliouk et al.
Art Unit	
Examiner Name	
Attorney Docket Number	5853-413

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[2]
TL		NIKISHIN et al., "High quality GaN grown on Si(111) by gas source molecular beam epitaxy with ammonia," Applied Physics Letters, 75:2073-2075, 1999	
TL		ZHANG et al., "Enhanced optical emission from GaN films grown on a silicon substrate," Applied Physics Letters, 74:1984-1986, 1999	
TL		LINTHICUM et al., "PROCESS ROUTES FOR LOW DEFECT-DENSITY GAN ON VARIOUS SUBSTRATES EMPLOYING PENDEO-EPITAXIAL GROWTH TECHNIQUES," MRS Internet J. Nitride Semicond. Res. 4S1, G4.9, 1999	
TL		STRITTMATTER et al., "Low-pressure metal organic chemical vapor deposition of GaN on silicon(111) substrates using an AlAs nucleation layer," Applied Physics Letters, 74:1242-1244, 1999	
TL		SANCHEZ-GARCIA et al., "Ultraviolet electroluminescence in GaN/AlGaN single-heterojunction light-emitting diodes grown on Si(111)," Journal of Applied Physics, 87:1569-1571, 2000	

Examiner Signature		Date Considered	6/18/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.
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TL		KRYLIOUK et al., "SINGLE CRYSTAL GaN SUBSTRATE GROWN by HYDRIDE-METAL ORGANIC VAPOR PHASE EPITAXY (H-MOVPE)," Electromechanical Society Proceedings, 98-18:99-107, 1998.	
TL		LUKAS et al., "OPTIMIZATION OF PHASE DIAGRAMS BY A LEAST SQUARES METHOD USING SIMULTANEOUSLY DIFFERENT TYPES OF DATA," CALPHAD, 1:225-236, 1977.	
TL		SUNDMAN et al., "THE THERMO-CALC DATABANK SYSTEM," CALPHAD, 9:153-190, 1985.	

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